For large diameters, \( G \) can be approximated with that for an infinite plane sample (section D.1). The influence of the finite diameter is the greater, the smaller \( t \). Therefore we have the upper limit for the influence of the periferi in the correction factor \( C_0 \) of section I.1 for a thin, circular slice, and we can write

\[
\varrho = G \frac{V}{I}, \quad 2\pi s \cdot T_1 \left( \frac{t}{s} \right) \cdot C_0 \left( \frac{d}{s} \right) \leq G \leq 2\pi s \cdot T_1 \left( \frac{t}{s} \right)
\]

where:

- \( 2\pi s \cdot T_1 \left( \frac{t}{s} \right) \) is the geometric factor for an infinite plane sample of thickness \( t \), and \( C_0 \left( \frac{d}{s} \right) \) is the diameter correction for a thin circular slice of diameter \( d \), when measuring in the center.
- \( T_1 \left( \frac{t}{s} \right) \) is found in section D.1, and \( C_0 \left( \frac{d}{s} \right) \) in section I.1.

**H.3) Probe Array Perpendicular to a Diameter at a fixed Distance from the Periferi.**

![Diagram](image)

This configuration has not been treated in the literature.

By a reasoning analogous to that in the previous section H.2, we conclude that

\[
\varrho = G \frac{V}{I}, \text{ where } 2\pi s \cdot T_1 \left( \frac{t}{s} \right) K_3 \left( \frac{L}{s} \frac{t}{s} \right) \leq G \leq 2\pi s \cdot D_{T_1} \left( \frac{L}{s} \frac{t}{s} \right)
\]

where:

- \( 2\pi s \cdot D_{T_1} \left( \frac{L}{s} \frac{t}{s} \right) \) is the geometric factor for a semi-infinite plane sample of thickness \( t \), when the probe array is parallel to the edge at a distance \( L \), (see section E.4), and \( 2\pi s \cdot T_1 \left( \frac{t}{s} \right) \) is the geometric factor for an infinite plane sample of thickness \( t \) (see section D.), and \( K_3 \left( \frac{L}{s} \frac{t}{s} \right) \) is the contour correction for the shown configuration, when \( t \ll s \) (see section I.4).